

Product Change Notification / JAON-18YDKI646

Date:	
Date.	

24-May-2022

Product Category:

Broadband Gateway

PCN Type:

Manufacturing Change

Notification Subject:

CCB 5014.002 Initial Notice: Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at MTAI assembly site.

Affected CPNs:

JAON-18YDKI646_Affected_CPN_05242022.pdf JAON-18YDKI646_Affected_CPN_05242022.csv

Notification Text:

PCN Status:Initial Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at MTAI assembly site.

Pre and Post Change Summary:

		Pre Change		Post Change			
	Die # 1	Global Foundries, Singapore - Fab 7 (GF07)		Global Foundries 7 (G	, Singapore - Fab F07)		
Fabrication Location	Die # 2	Global Foundries, Singapore - Fab 2 (GF02)	Microchip Technology Colorado – Fab 5 (MCSO)	Global Foundries, Singapore - Fab 2 (GF02)	Microchip Technology Colorado – Fab 5 (MCSO)		
Die Size	Die # 1	·		1.932x1.860mm ost change comparison for Die # 1 cation			
	Die # 2	1.57 x 1	.72 mm	1.57 x 1.72 mm			
Assemb	ly Site	Microchip Technology Thailand (HQ) (MTAI)		Microchip Technology Thailand (HQ) (MTAI)			
Wire Material		CuPdAu		CuPdAu			
Die Attach Material		32	80	3280			
Molding Compound Material		G700	OLTD	G700	OLTD		
Lead Frame	Material	A1	94	A1	94		

Impacts to Data Sheet:None

Change ImpactNone

Reason for Change:To improve productivity by qualifying a new die size.

Change Implementation Status:In Progress

Estimated Qualification Completion Date:June 2022

Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	May 2022				Jur	ne 20)22		
Workweek	1	2	2	2	2	2	2	2	2
Workweek	9	0	1	2	3	4	5	6	7
Initial PCN Issue									
Date				Х					
Qual Report							Х		
Availability							^		
Final PCN Issue							Х		
Date							^		

Method to Identify Change:Traceability code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History:May 24, 2022: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_JAON-18YDKI646_Pre and Post Change_Summary.pdf PCN_JAON-18YDKI646_Qual_Plan.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



QUALIFICATION PLAN SUMMARY

PCN #: JAON-18YDKI646

Date: April 20, 2022

Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at MTAI assembly site.

Purpose:

Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at MTAI assembly site.

CCB No.: 5014.002

	Assembly site	MTAI
	BD Number	BD-000490-01
	MP Code (MPC)	3410X to 3413J 3411Y to 3413K
Misc.	Part Number (CPN)	Le9641
Ξ	MSL information	MSL3
	Assembly Shipping Media (T/R, Tube/Tray)	Tray and T/R
	Base Quantity Multiple (BQM)	1300
	Reliability Site	MTAI
	Paddle size	232 x 232 mils
	Material	A194
	DAP Surface Prep	Selective Ag Plating
<u>9</u>	Treatment	ВОТ
ran	Process	Etched
Lead-Frame	Lead-lock	Yes
الد	Part Number	10104808
	Lead Plating	Matte Tin
	Strip Size	250x70mm
	Strip Density	240 units/strip
Bond Wire	Material	CuPdAu
<u>Die</u> Attach	Part Number	3280
Ati	Conductive	yes
MC	Part Number	G700LTD
	PKG Type	VQFN
(D)	Pin/Ball Count	48
PKG	PKG width/size	7x7
	Die Size	1.932x1.860mm

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Wire Sweep	Max limit 15%	77	0	1	77	No shorting		Due to long wires
Preconditioning - Required for surface mount devices	+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C.	154	15	1	169	0	15	Spares should be properly identified.



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN #: JAON-18YDKI646

Date: April 2, 2021

Qualification of MTAI as an additional assembly site for selected MSCC products available in 48L VQFN (7x7x1mm) package.



Purpose Qualification of MTAI as an additional assembly site for selected MSCC products

available in 48L VQFN (7x7x1mm) package.

CN ES351324

QUAL ID R2100011 rev. C **MP CODE** 3411H7M9CA01

Part No. LE9652PQC

Bonding No. BDM-002786 Rev. A

CCB No. 4514

Package

Type 48L VQFN

Package size 7x7x1.0 mm

Lead Frame

Paddle size 232 x 232 mils

Material A194

Surface Ag selective Plated

Process Etched
Lead Lock Yes

Part Number 10104808

Material

Epoxy 3280

Wire CuPdAu wire Mold Compound G700LTD

Plating Composition Matte Tin



Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI213802513.000	GF07921225657.200	2051C75
MTAI213802989.000	GF07921225657.200	2051DQ0
MTAI213802998.000	GF07921225657.200	2051DW 3

Result	Pass F	Fail		
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48L VQFN (7x7x1.0 mm) assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks		
Precondition Prior Perform	Electrical Test: +25°C System: CHROMA3650	JESD22- A113	693(0)	693		Good Devices		
Reliability Tests (At MSL Level 3)	Bake 150°C, 24 hrs System: CHINEE	JIP/ IPC/JEDEC		693				
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		693				
	3x Convection-Reflow 265°C max			693				
	System: Vitronics Soltec MR1243 Electrical Test: +25°C System: CHROMA3650			0/693	Pass			

	PACKAGE QUALIFIC	ATION	IREP	ORT		
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +25°C System: CHROMA3650	JESD22- A104	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
Temp Cycle	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +25°C System: CHROMA3650		231(0)	231 0/231	Pass	
	Bond Strength: Wire Pull (> 2.5 grams) Bond Shear (>15.00 grams)		15 (0) 15 (0)	0/15 0/15	Pass Pass	
	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C
UNBIASED- HAST	Electrical Test: +25°C System: CHROMA3650		231(0)	0/231	Pass	77 units / lot
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			231		
	Electrical Test: +25°C System: CHROMA3650		231(0)	0/231	Pass	

	PACKAGE QUALIFIC	ATION	NREF	PORT	•	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units
	Electrical Test: +25°C System: CHROMA3650		45(0)	0/45	Pass	
Solderability	Steam Aging: Temp 93°C,8Hrs System: SAS-3000	J-STD-002	22 (0)	22		
Temp 215°C	Solder Dipping: Solder Temp.215°C Solder material: SnPb Sn63, Pb37 System: ERSA RA 2200D Visual Inspection: External Visual Inspection			22 0/22	Pass	
Solderability	Steam Aging: Temp 93°C,8Hrs System: SAS-3000	J-STD-002	22 (0)	22		
Temp 245°C	Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6			22		
	System: ERSA RA 2200D Visual Inspection: External Visual Inspection			0/22	Pass	
Bond Strength	Wire Pull (> 2.5 grams)	Mil.Std. 883-2011	30 (0) Wires	0/30	Pass	
Data Assembly	Bond Shear (>15.00 grams)	CDF-AEC- Q100-001	30 (0) bonds	0/30	Pass	

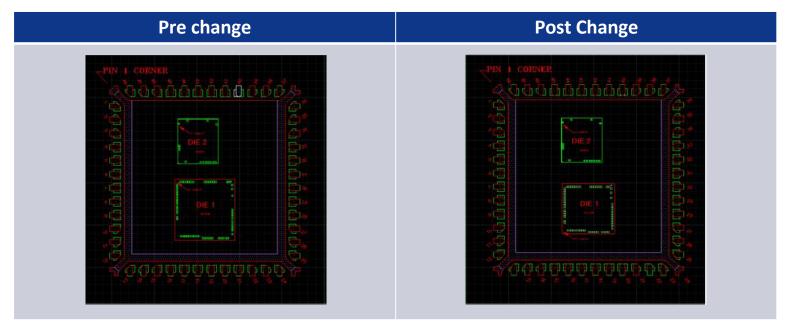
CCB 5014.002 Pre and Post Change Summary PCN#: JAON-18YDKI646



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Pre and post change comparison



Note: Not-to-scale



JAON-18YDKI646 - CL LE9651PQL LE9641PQL and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN

Affected Catalog Part Numbers(CPN)

LE9641PQC

LE9651PQC

LE9641PQCT

LE9651PQCT